

<b>Notice of References Cited</b>	Application/Control No. 09/883,440	Applicant(s)/Patent Under Reexamination DE LANGE ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,929,849	07-1999	Kikinis, Dan	725/113
	B	US-6,756,997	06-2004	Ward et al.	715/716
	C	US-2002/0056086	05-2002	Yuen, Henry C.	725/9
	D	US-2002/0056094	05-2002	DUREAU, VINCENT	725/38
	E	US-2004/0261127	12-2004	Freeman et al.	725/135
	F	US-6,571,344	05-2003	Sitnik, Eran	713/502
	G	US-2002/0059629	05-2002	Markel, Steven O.	725/100
	H	US-2005/0125823	06-2005	McCoy et al.	725/034
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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